74ABT541

Octal buffer/line driver; 3-state Rev. 3 — 11 August 2014

Product data sheet

1. **General description**

The 74ABT541 high-performance BiCMOS device combines low static and dynamic power dissipation with high speed and high output drive.

The 74ABT541 device is an octal buffer that is ideal for driving bus lines. The outputs are all capable of sinking 64 mA and sourcing 32 mA. The device features input and outputs on opposite sides of the package to facilitate printed circuit board layout.

2. **Features and benefits**

- Octal bus interface
- Functions similar to the 74ABT241
- Provides ideal interface and increases fan-out of MOS microprocessors
- Efficient pinout to facilitate PC board layout
- 3-State buffer outputs sink 64 mA and source 32 mA
- Live insertion/extraction permitted
- Power-up 3-state
- Latch-up protection exceeds 500 mA per JESD78 class II level A
- ESD protection:
 - ♦ HBM JESD22-A114E exceeds 2000 V
 - MM JESD22-A115-A exceeds 200 V

3. **Ordering information**

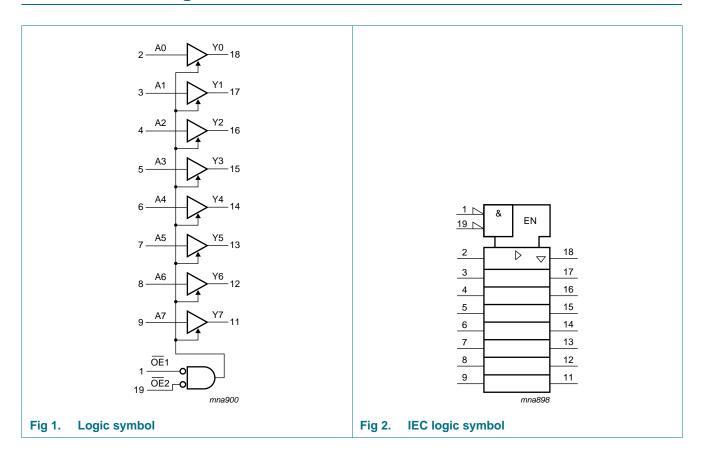
Table 1. **Ordering information**

Type number	Package									
	Temperature range	Name	Description	Version						
74ABT541N	–40 °C to +85 °C	DIP20	plastic dual in-line package; 20 leads (300 mil)	SOT146-1						
74ABT541D	–40 °C to +85 °C	SO20	plastic small outline package; 20 leads; body width 7.5 mm	SOT163-1						
74ABT541DB	−40 °C to +85 °C	SSOP20	plastic shrink small outline package; 20 leads; body width 5.3 mm	SOT339-1						
74ABT541PW	−40 °C to +85 °C	TSSOP20	plastic thin shrink small outline package; 20 leads; body width 4.4 mm	SOT360-1						



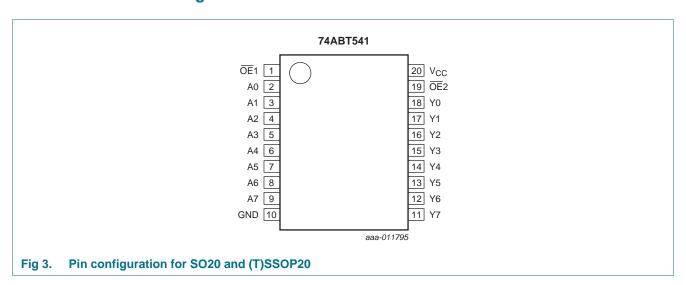
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4. Functional diagram



5. Pinning information

5.1 Pinning



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5.2 Pin description

Table 2. Pin description

Symbol	Pin	Description
OE1, OE2	1, 19	output enable input (active LOW)
A[0:7]	2, 3, 4, 5, 6, 7, 8, 9	data input
GND	10	ground (0 V)
Y[0:7]	18, 17, 16, 15, 14, 13, 12, 11	data output
V_{CC}	20	supply voltage

6. Functional description

Table 3. Functional table[1]

Control		Input	Output		
OE1	OE2	An	Yn		
L	L	L	L		
L	L	Н	Н		
X	Н	X	Z		
Н	X	X	Z		

^[1] H = HIGH voltage level; L = LOW voltage level; X = don't care; Z = high-impedance OFF-state.

7. Limiting values

Table 4. Limiting values[3]

In accordance with the Absolute Maximum Rating System (IEC 60134). Voltages are referenced to GND (ground = 0 V).

Symbol	Parameter	Conditions		Min	Max	Unit
V _{CC}	supply voltage			-0.5	+7.0	V
VI	input voltage		[1]	-1.2	+7.0	V
Vo	output voltage	output in OFF-state or HIGH-state	[2]	-0.5	+5.5	V
I _{IK}	input clamping current	V _I < 0 V		-18	-	mA
I _{OK}	output clamping current	V _O < 0 V		-50	-	mA
Io	output current	output in LOW-state		-	128	mA
Tj	junction temperature		[3]	-	150	°C
T _{stg}	storage temperature			-65	+150	°C
P _{tot}	total power dissipation	$T_{amb} = -40 ^{\circ}\text{C} \text{ to } +85 ^{\circ}\text{C}$	[4]	-	500	mW

^[1] The minimum input voltage ratings may be exceeded if the input current ratings are observed.

^[2] The output voltage ratings may be exceeded if the output current ratings are observed.

^[3] The performance capability of a high-performance integrated circuit in conjunction with its thermal environment can create junction temperatures which are detrimental to reliability.

^[4] For SO20 packages: above 70 °C the value of P_{tot} derates linearly with 8 mW/K. For (T)SSOP20 packages: above 60 °C the value of P_{tot} derates linearly with 5.5 mW/K.

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8. Recommended operating conditions

 Table 5.
 Operating conditions

Voltages are referenced to GND (ground = 0 V).

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
V _{CC}	supply voltage		4.5	-	5.5	V
VI	input voltage		0	-	V _{CC}	V
V_{IH}	HIGH-level input voltage		2.0	-	-	V
V_{IL}	LOW-level input voltage		-	-	0.8	V
I _{OH}	HIGH-level output current		-32	-	-	mA
I _{OL}	LOW-level output current		-	-	64	mA
Δt/ΔV	input transition rise and fall rate		0	-	5	ns/V
T _{amb}	ambient temperature	in free air	-40	-	+85	°C

9. Static characteristics

Table 6. Static characteristics

At recommended operating conditions. Voltages are referenced to GND (ground = 0 V).

Symbol	Parameter	Conditions		25 °C			–40 °C t	Unit	
				Min	Тур	Max	Min	Max	
V _{IK}	input clamping voltage	$V_{CC} = 4.5 \text{ V}; I_{IK} = -18 \text{ mA}$		-	-0.9	-1.2	-	-1.2	V
V _{OH}	HIGH-level output	$V_I = V_{IL}$ or V_{IH}							
	voltage	$V_{CC} = 4.5 \text{ V}; I_{OH} = -3 \text{ mA}$		2.5	2.9	-	2.5	-	V
		$V_{CC} = 5.0 \text{ V}; I_{OH} = -3 \text{ mA}$		3.0	3.4	-	3.0	-	V
		$V_{CC} = 4.5 \text{ V}; I_{OH} = -32 \text{ mA}$		2.0	2.4	-	2.0	-	V
V _{OL}	LOW-level output voltage	V_{CC} = 4.5 V; I_{OL} = 64 mA; V_I = V_{IL} or V_{IH}		-	0.42	0.55	-	0.55	V
l _l	input leakage current	$V_{CC} = 5.5 \text{ V}; V_I = \text{GND or } 5.5 \text{ V}$		-	±0.01	±1.0	-	±1.0	μΑ
I _{OFF}	power-off leakage current	V_{CC} = 0.0 V; V_{I} or $V_{O} \le 4.5$ V		-	±5.0	±100	-	±100	μΑ
I _{O(pu/pd)}	power-up/power-down output current	V_{CC} = 2.0 V; V_{O} = 0.5 V; V_{I} = GND or V_{CC} ; \overline{OE} = don't care	[1]	-	±5.0	±50	-	±50	μΑ
l _{OZ}	OFF-state output	$V_{CC} = 5.5 \text{ V}; V_I = V_{IL} \text{ or } V_{IH}$							
	current	V _O = 2.7 V		-	5.0	50	-	50	μΑ
		V _O = 0.5 V		-	-5.0	-50	-	-50	μΑ
I _{LO}	output leakage current	HIGH-state; $V_O = 5.5 \text{ V}$; $V_{CC} = 5.5 \text{ V}$; $V_I = \text{GND or } V_{CC}$		-	5.0	50	-	50	μΑ
Io	output current	$V_{CC} = 5.5 \text{ V}; V_{O} = 2.5 \text{ V}$	[2]	-40	-100	-180	-40	-180	mA
I _{CC}	supply current	$V_{CC} = 5.5 \text{ V}; V_I = \text{GND or } V_{CC}$							
		outputs HIGH-state		-	0.5	250	-	250	μΑ
		outputs LOW-state		-	24	30	-	30	mA
		outputs disabled		-	0.5	250	-	250	μΑ

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Table 6. Static characteristics ...continued

At recommended operating conditions. Voltages are referenced to GND (ground = 0 V).

Symbol	Parameter	Conditions		25 °C			–40 °C to	o +85 °C	Unit
				Min	Тур	Max	Min	Max	
Δl _{CC}	additional supply current	per input pin; output enabled; V_{CC} = 5.5 V; one input at 3.4 V, other inputs at V_{CC} or GND	[3]	-	0.5	1.5	-	1.5	mA
		per input pin; output disabled; $V_{CC} = 5.5 \text{ V}$; one data input at 3.4 V, other inputs at V_{CC} or GND		-	0.5	50	-	50	μΑ
		per input pin; output disabled; $V_{CC} = 5.5 \text{ V}$; one enable input at 3.4 V, other inputs at V_{CC} or GND		-	0.5	1.5	-	1.5	mA
C _I	input capacitance	V _I = 0 V or V _{CC}		-	4	-	-	-	pF
Co	output capacitance	outputs disabled; $V_O = 0 \text{ V or } V_{CC}$		-	7	-	-	-	pF

^[1] This parameter is valid for any V_{CC} between 0 V and 2.1 V, with a transition time of up to 10 ms. From V_{CC} = 2.1 V to V_{CC} = 5 V \pm 10 %, a transition time of up to 100 μ s is permitted.

10. Dynamic characteristics

Table 7. Dynamic characteristics

GND = 0 V. Test circuit is shown in Figure 6.

Symbol	Parameter	Conditions	25 °C; V	_{CC} = 5.0	V	-40 °C to +8 V _{CC} = 5.0 V	Unit	
			Min	Тур	Max	Min	Max	
t _{PLH}	LOW to HIGH propagation delay	An to Yn, see Figure 4	1.0	2.6	4.1	1.0	4.6	ns
t _{PHL}	HIGH to LOW propagation delay	An to Yn, see Figure 4	1.0	2.9	4.2	1.0	4.6	ns
t _{PZH}	OFF-state to HIGH propagation delay	OEn to Yn; see Figure 5	1.1	3.1	4.8	1.1	5.3	ns
t _{PZL}	OFF-state to LOW propagation delay	OEn to Yn; see Figure 5	2.1	4.4	5.9	2.1	6.4	ns
t _{PHZ}	HIGH to OFF-state propagation delay	OEn to Yn; see Figure 5	2.1	5.1	6.6	2.1	7.1	ns
t _{PLZ}	LOW to OFF-state propagation delay	OEn to Yn; see Figure 5	1.7	4.7	6.2	1.7	6.7	ns

^[2] Not more than one output should be tested at a time, and the duration of the test should not exceed one second.

^[3] This is the increase in supply current for each input at 3.4 V.

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11. AC waveforms

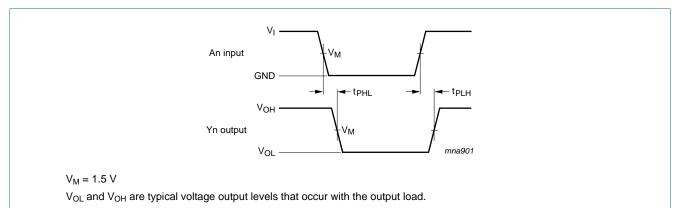
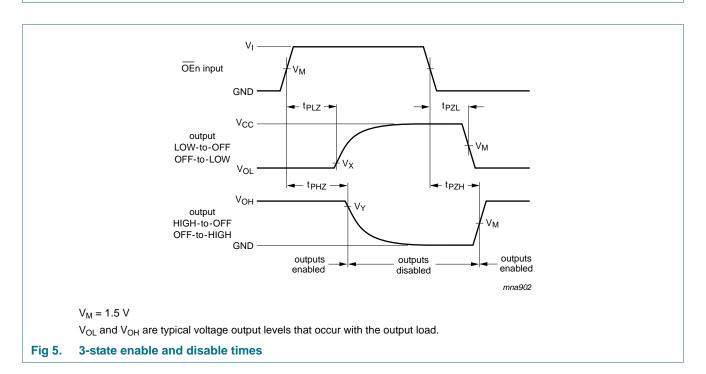
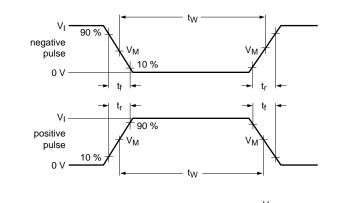
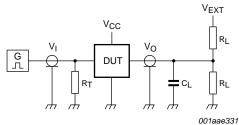


Fig 4. Input (An) to output (Yn) propagation delays



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Test data is given in Table 8.

Test circuit definitions:

 R_L = Load resistance.

 C_L = Load capacitance including jig and probe capacitance.

 R_T = Termination resistance should be equal to output impedance Z_0 of the pulse generator.

 V_{EXT} = Test voltage for switching times.

Fig 6. Test circuit for measuring switching times

Table 8. Test data

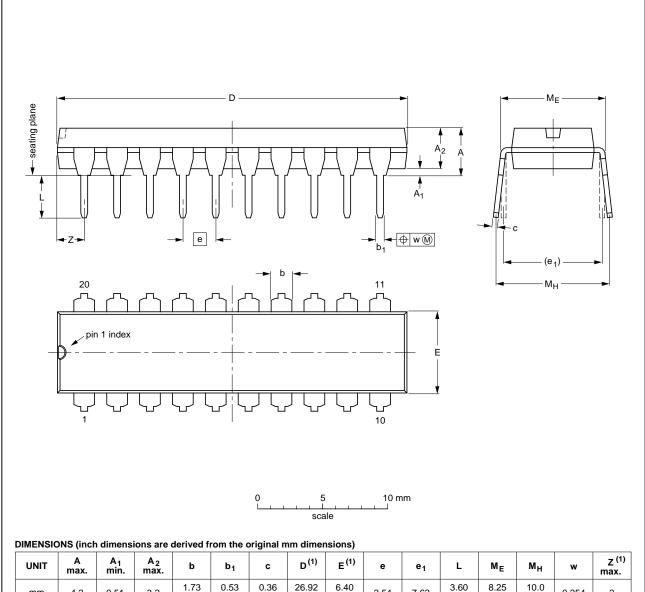
I	nput				Load		V _{EXT}		
١	٧ı	f _l	t _W	t _r , t _f	CL	R_L	t _{PHL} , t _{PLH}	t _{PZH} , t _{PHZ}	t_{PZL}, t_{PLZ}
3	3.0 V	1 MHz	500 ns	≤ 2.5 ns	50 pF	500 Ω	open	open	7.0 V

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12. Package outline

DIP20: plastic dual in-line package; 20 leads (300 mil)

SOT146-1



UNIT	A max.	A ₁ min.	A ₂ max.	b	b ₁	С	D ⁽¹⁾	E ⁽¹⁾	е	e ₁	L	ME	Мн	w	Z ⁽¹⁾ max.
mm	4.2	0.51	3.2	1.73 1.30	0.53 0.38	0.36 0.23	26.92 26.54	6.40 6.22	2.54	7.62	3.60 3.05	8.25 7.80	10.0 8.3	0.254	2
inches	0.17	0.02	0.13	0.068 0.051	0.021 0.015	0.014 0.009	1.060 1.045	0.25 0.24	0.1	0.3	0.14 0.12	0.32 0.31	0.39 0.33	0.01	0.078

Note

1. Plastic or metal protrusions of 0.25 mm (0.01 inch) maximum per side are not included.

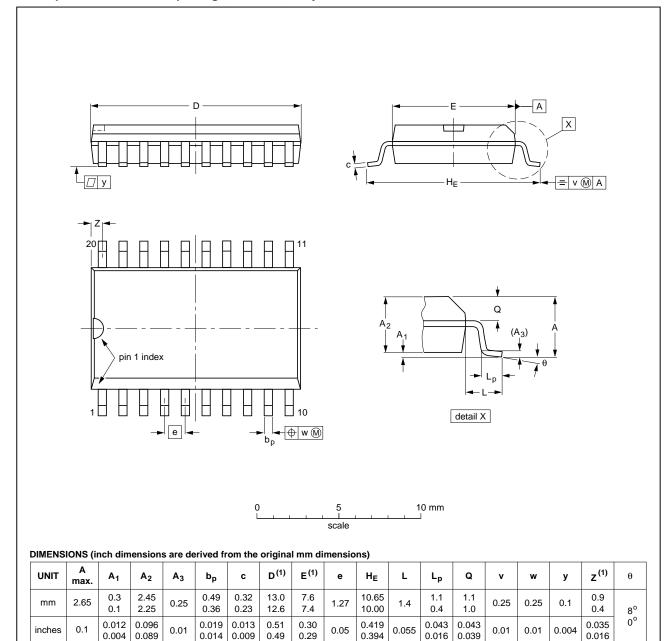
VERSION IEC JEDEC JEITA PROJECTION SOT146-1 MS-001 SC-603 IIIIIIIIIIIIIIIIIIIIIIIIIIIIIIIIIIII	OUTLINE		REFER	ENCES	EUROPEAN	ISSUE DATE
SO(1146-1) $MS-001$ $SC-603$ $MS-001$ $MS-001$	VERSION	IEC	JEDEC	JEITA	PROJECTION	1330E DATE
- + 00 02 10	SOT146-1		MS-001	SC-603		99-12-27 03-02-13

Fig 7. Package outline SOT146-1 (DIP20)

74ABT541

SO20: plastic small outline package; 20 leads; body width 7.5 mm

SOT163-1



Note

1. Plastic or metal protrusions of 0.15 mm (0.006 inch) maximum per side are not included.

OUTLINE		REFER	ENCES	EUROPEAN	ISSUE DATE
VERSION	IEC	JEDEC	JEITA	PROJECTION	ISSUE DATE
SOT163-1	075E04	MS-013			99-12-27 03-02-19

Fig 8. Package outline SOT163-1 (SO20)

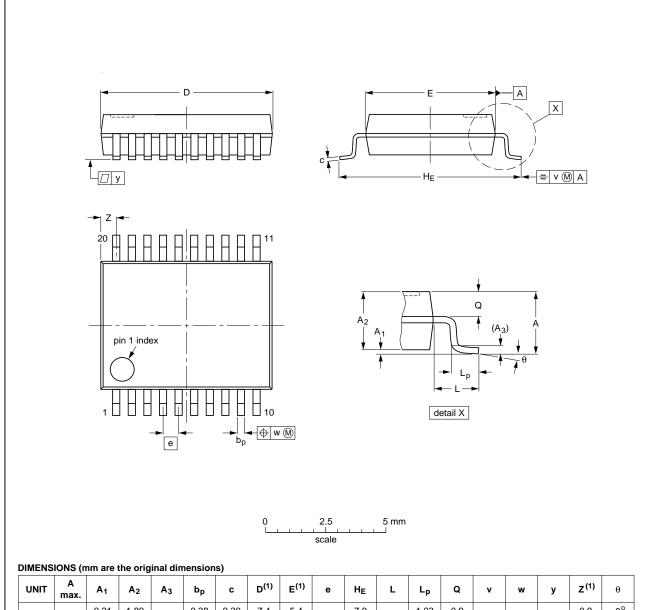
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SSOP20: plastic shrink small outline package; 20 leads; body width 5.3 mm

SOT339-1



UNIT	A max.	A ₁	A ₂	A ₃	bp	С	D ⁽¹⁾	E ⁽¹⁾	е	HE	L	Lp	Q	v	w	у	z ⁽¹⁾	θ
mm	2	0.21 0.05	1.80 1.65	0.25	0.38 0.25	0.20 0.09	7.4 7.0	5.4 5.2	0.65	7.9 7.6	1.25	1.03 0.63	0.9 0.7	0.2	0.13	0.1	0.9 0.5	8° 0°

Note

1. Plastic or metal protrusions of 0.2 mm maximum per side are not included.

OUTLINE		REFER	EUROPEAN	ISSUE DATE			
VERSION	IEC	JEDEC	JEITA		PROJECTION	ISSUE DATE	
SOT339-1		MO-150				99-12-27 03-02-19	

Fig 9. Package outline SOT339-1 (SSOP20)

74ABT541

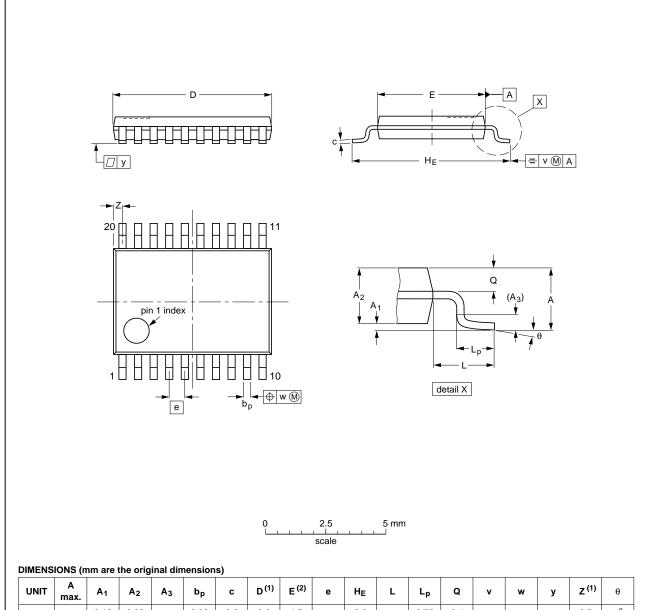
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TSSOP20: plastic thin shrink small outline package; 20 leads; body width 4.4 mm

SOT360-1



UNIT	A max.	A ₁	A ₂	A ₃	bp	С	D ⁽¹⁾	E ⁽²⁾	е	HE	L	Lp	ø	v	w	у	Z ⁽¹⁾	θ
mm	1.1	0.15 0.05	0.95 0.80	0.25	0.30 0.19	0.2 0.1	6.6 6.4	4.5 4.3	0.65	6.6 6.2	1	0.75 0.50	0.4 0.3	0.2	0.13	0.1	0.5 0.2	8° 0°

Notes

- 1. Plastic or metal protrusions of 0.15 mm maximum per side are not included.
- 2. Plastic interlead protrusions of 0.25 mm maximum per side are not included.

OUTLINE		REFER	EUROPEAN	ISSUE DATE			
VERSION	IEC	JEDEC	JEITA		PROJECTION	ISSUE DATE	
SOT360-1		MO-153				-99-12-27 03-02-19	
SOT360-1		MO-153					

Fig 10. Package outline SOT360-1 (TSSOP20)

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13. Abbreviations

Table 9. Abbreviations

Acronym	Description
BiCMOS	Bipolar Complementary Metal-Oxide Semiconductor
CDM	Charged Device Model
DUT	Device Under Test
ESD	ElectroStatic Discharge
HBM	Human Body Model
MM	Machine Model

14. Revision history

Table 10. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes					
74ABT541 v.3	20140811	Product data sheet	-	74ABT541 v.2					
Modifications:	 The format of this data sheet has been redesigned to comply with the new identity guidelines of NXP Semiconductors. Legal texts have been adapted to the new company name where appropriate. 								
74ABT541 v.2	19980116	Product specification	-	74ABT541 v.1					
74ABT541 v.1	19960110	Product specification	-	-					

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15.1 Data sheet status

Document status[1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

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